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Report No.: SZEM150300112702
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SAR Evaluation Report

Application No.: SZEM1503001127CR
Applicant: WOOX Innovations Limited
Manufacturer: WOOX Innovations Limited
Factory: Innovation Sound Technology Co.Ltd
Product Name: Bluetooth headphone
Model No.(EUT): SHB3165
Add Model No.: SHB3165/XX,SHB3165YY/XX
SHB3185,SHB3185/XX,SHB3185YY/XX
SHB3060,SHB3060/XX,SHB3060YY/XX
SHB3080,SHB3080/XX,SHB3080YY/XX
(XX=00-99,YY=AA-ZZ)
Trade Mark: Philips
FCC ID: 2AANUSHB3060
47 CFR Part 1.1307 (2014)
Standards: 47 CFR Part 2.1093 (2014)
KDB447498D01 General RF Exposure Guidance v05r02
Date of Receipt: 2015-03-17
Date of Test: 2015-03-24 to 2015-03-31
Date of Issue: 2015-04-08

Test Result :	PASS*
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* In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Jack Zhang
EMC Laboratory Manager

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

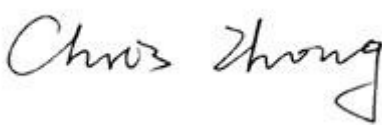
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2 Version

Revision Record				
Version	Chapter	Date	Modifier	Remark
00		2015-04-08		Original

Authorized for issue by:			
Tested By		 (Chris Zhong) /Project Engineer	2015-03-24
			Date
Prepared By		 (Jade Chen) /Clerk	2015-04-08
			Date
Checked By		 (Owen Zhou) /Reviewer	2015-04-08
			Date



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4 General Information

4.1 Client Information

Applicant:	WOOX Innovations Limited
Address of Applicant:	5/F, Philips Electronics Building, 5 Science Park East Avenue, HongKong Science Park, Shatin, New Territories, HongKong.
Manufacturer:	WOOX Innovations Limited
Address of Manufacturer:	5/F, Philips Electronics Building, 5 Science Park East Avenue, HongKong Science Park, Shatin, New Territories, HongKong.
Factory:	Innovation Sound Technology Co., LTD
Address of Factory:	Building 2nd, Industrial Area of Huaide Cuihai Fengtang Road, Fuyong Town, Shenzhen, China

4.2 General Description of EUT

Product Name:	Bluetooth headphone	
Model No.:	SHB3165	
Trade Mark:	Philips	
Operation Frequency:	2402MHz~2480MHz	
Bluetooth Version:	V3.0+EDR	
Modulation Technique:	Frequency Hopping Spread Spectrum(FHSS)	
Modulation Type:	GFSK, $\pi/4$ DQPSK, 8DPSK	
Number of Channel:	79	
Hopping Channel Type:	Adaptive Frequency Hopping systems	
Test Power Grade:	ClassII (manufacturer declare)	
Test Software of EUT:	RF Control kit (manufacturer declare)	
Sample Type:	Portable production	
Antenna Type	Integral	
Antenna Gain	0.5dBi	
Power Supply:	USB Charge :DC 5V 0.5A	
	Battery :	DC 3.7V 230mAh
USB Cable:	Unshielded 55cm	

Remark:

Model No.: SHB3165, SHB3165/XX, SHB3185, SHB3185/XX, SHB3185YY/XX, SHB3060, SHB3060/XX, SHB3080, SHB3080/XX, SHB3080YY/XX (XX=00-99, YY=AA-ZZ)

Only the Model SHB3165 was tested, since the electrical circuit design, layout, components used and internal wiring were identical for all above models. Only different on:

1. SHB3080 is only Bluetooth device name different from SHB3060.
2. SHB3185 is only Bluetooth device name different from SHB3165.
3. SHB3165, SHB3185 only adds passive NFC, different device name and housing with NCVM different from SHB3060, SHB3080.



4.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch E&E Lab

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China
518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.



4.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **CNAS (No. CNAS L2929)**

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

- **VCCI**

The 10m Semi-anechoic chamber and Shielded Room (7.5m x 4.0m x 3.0m) of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

- **FCC – Registration No.: 556682**

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 556682.

- **Industry Canada (IC)**

Two 3m Semi-anechoic chambers of SGS-CSTC Standards Technical Services Co., Ltd. have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1 & 4620C-2.

4.5 Deviation from Standards

None.

4.6 Abnormalities from Standard Conditions

None.

4.7 Other Information Requested by the Customer

None.



5 SAR Evaluation

5.1 RF Exposure Compliance Requirement

5.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v05r02

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

5.1.2 Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$\left[\frac{(\text{max. power of channel, including tune-up tolerance, mW})}{(\text{min. test separation distance, mm})} \right] \cdot \sqrt{f(\text{GHz})} \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}$$

$f(\text{GHz})$ is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

5.1.3 EUT RF Exposure

The Max Conducted Peak Output Power is 3.33dBm in middle channel(2.441GHz);

The best case gain of the antenna is 0.5dBi.

$\text{EIRP} = 3.33\text{dBm} + 0.5\text{dBi} = 3.83\text{dBm}$

3.83dBm logarithmic terms convert to numeric result is nearly 2.415mW

According to the formula. calculate the EIRP test result:

$$\left[\frac{(\text{max. power of channel, including tune-up tolerance, mW})}{(\text{min. test separation distance, mm})} \right] \cdot \sqrt{f(\text{GHz})}$$

General RF Exposure = $(2.415\text{mW} / 5 \text{ mm}) \times \sqrt{2.441\text{GHz}} = 0.7546$ ①

SAR requirement:

$S = 3.0$

② ;

① < ②.

So the SAR report is not required.